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Powder Diffraction

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On the Cover: The Cover Figure shows a cluster analysis (top left) of the dominant excipients present in the XRD analyses of 65 formulated pharma-ceutical diffraction patterns. The bottom two figures show stacked plots of the raw data for all the patterns falling into two of the clusters. The top right figure shows the XRD analysis of one of the formulated pharmaceutical diffraction patterns and the results of phase identification of β -lactose (blue), celluose I β (green) and the API Invokana[®] (red).

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